



IEC TS 62804-1:2015

Photovoltaic (PV) Modules - Test Methods for the detection of potential-induced degradation

Part 1: Crystalline silicon
Confirmation of test results

VDE Renewables File Ref.: 10011/ ET-20221016-187

Applicant: Wuxi Suntech Power Co., Ltd.
16 Xin Hua Road, Xinwu District, 214028 Wuxi City, China

Product: Crystalline silicon Photovoltaic (PV)-Modules

Type: A) STPXXXS-C72/Nsh+ B) STPXXXS-C54/Nshb+
B) STPXXXS-C54/Nsh+ B) STPXXXS-C54/Nshm+
B) STPXXXS-C54/Nshtb+ B) STPXXXS-C54/Nshkm+
B) STPXXXS-C54/Nshk+

XXX in the type replace the power in Watt and can be any number between:
545 – 595 for A); 405 – 445 for B)

Manufacturer: Wuxi Suntech Power Co., Ltd.

Standard: IEC TS 62804-1:2015

Test conditions

Testing time: 192 h

Chamber temperature: 85°C

Relative Humidity: 85 %

Potential to ground: ± 1500 V

Pass criteria

Power degradation: < 5%

Dry Insulation: > 40 M Ω m²

Wet insulation: > 40 M Ω m²



Summary of test results:

Maximum power degradation:	allowed	max. 5 %
	measured	max. 2.01 %

The measured degradation is below the allowed degradation.

Dry insulation resistance:	required	min. 15.5 M Ω
	measured	>500 M Ω

The measured dry insulation resistance is above the minimum required dry insulation resistance.

Wet insulation resistance:	required	min. 15.5 M Ω
	measured	>500 M Ω

The measured wet insulation resistance is above the minimum required wet insulation resistance.

Visual inspection: No findings

The complete test results and the relevant bill of materials are given in Test Report No.: TRPVM-ET-20221016-187-3.

VDE Renewables GmbH

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Shanghai, 2024-06-19

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